

# Japan TC Chapter FPD Metrology Global Technical Committee

## Liaison Report

May 2018

V1.0

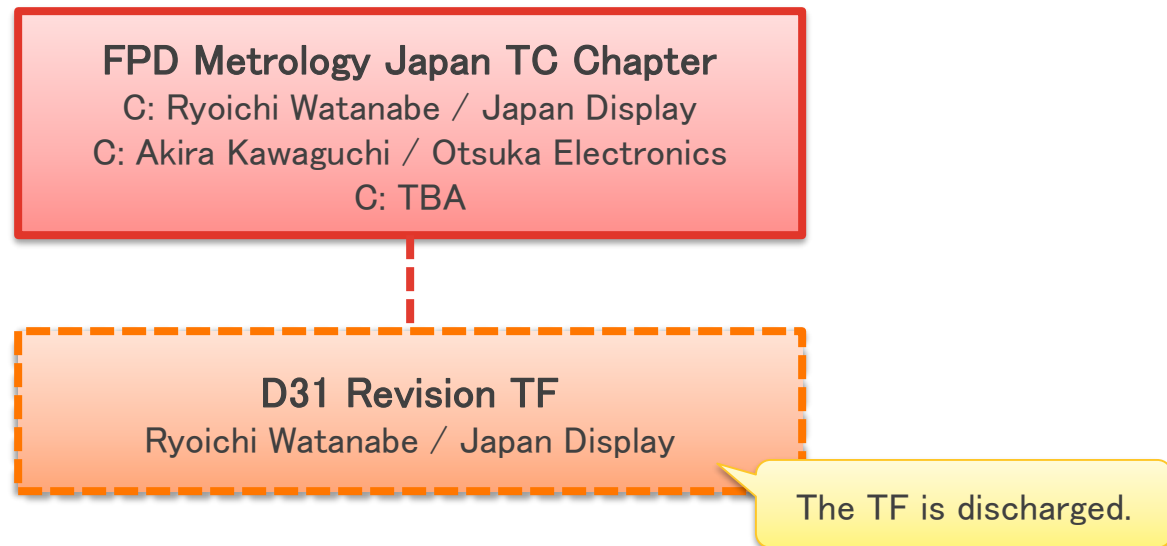
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# Leadership

- Committee Co-chairs
  - Ryoichi Watanabe / Japan Display
  - Akira Kawaguchi / Otsuka Electronics

# Current Committee Structure



# Meeting Information

- Last Meeting
  - Monday, May 28, 2018
    - During Japan Standards Spring 2018 Meetings
    - SEMI Japan, Tokyo
- Next Meeting
  - October, 2018 (Date to be decided)
    - During Japan Standards Fall 2018 Meetings
    - SEMI Japan, Tokyo
    - ✓ This TC Chapter meeting will not be jointly held with FPD Materials & Components

<http://www.semi.org/en/standards-events>

# Committee Activities

- Ballot: None
- New Activities: None
- Five Year Review: None
- SNARF Abolished: None

# Task Force Updates

- D31 Revision Task Force
  - Doc.6101, Line Item Revision to SEMI D31-0213, with title change from “Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection” to “Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection”
    - Line Item 1: Correct title and concomitant text of SEMI D31
      - Passed as balloted at the TC Chapter meeting on April 7, 2017
      - Passed at A&R in May, 2017
      - Published as SEMI D31-0318
  - The TC Chapter approved the TF’s discharge at the meeting on May 28, 2018

# Thank you!

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